

HP/Agilent 3070 Series



The HP/Agilent 3070 Series test systems provide a wide variety of board testing capabilities. These systems perform in-circuit, functional, or combinational testing on digital, analog and hybrid circuit boards.

FEATURES

High Speed Testing: Rate: Up to 20 million / sec.

High Speed Clocks: 625 kHz to 80 MHz

Digital Functional Testing Tools

Timing sets

POWERED TESTING

Digital Component Testing Library-based
digital in-circuit
component testing.

5184 hybrid nodes maximum

6.25 million patterns per second

625 kHz to 20 MHz clocks

Flash RAM programming capability

Boundary-scan testing.

UNPOWERED TESTING

Maximum System Capacity: 5184 hybrid nodes

Opens Testing: Circuit opens detected with
Agilent TestJet* technology.

Shorts Testing: Automatic test with
programmable threshold.

TEST METHODS

Shorts & opens

Analog in-circuit

Analog functional

Mixed analog & digital

Digital in-circuit

Digital functional

Boundary -scan

ANALOG FUNCTIONAL TESTING:

Library and user-developed testing of
Op-amps, comparators, voltage regulators,
etc.

DIGITAL COMPONENT TESTING:

Library-based digital in-circuit
component testing

5184 hybrid nodes maximum

6.25 million patterns per second

625 kHz to 20 MHz clocks

Flash RAM programming capability

Boundary-scan testing

ANALOG COMPONENT TESTING:

Resistance, capacitance and inductance.

Polarity verification on polarized SMT
and axial capacitors.

Special tests for diodes, zener diodes, transistors,
FETs, jumpers, switches and potentiometers.



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